

Figure 0-1. Pin Configurations

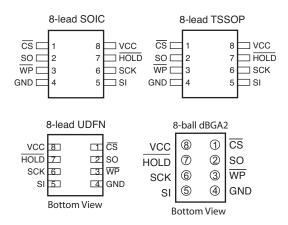


Table 0-1. Pin Configurations

Pin	Function
CS	Chip Select
SCK	Serial Data Clock
SI	Serial Data Input
so	Serial Data Output
GND	Ground
V _{CC}	Power Supply
WP	Write Protect
HOLD	Suspends Serial Input
NC	No Connect

Block Write protection is enabled by programming the status register with top $\frac{1}{4}$, top $\frac{1}{2}$ or entire array of write protection. Separate Program Enable and Program Disable instructions are provided for additional data protection. Hardware data protection is provided via the $\overline{\text{WP}}$ pin to protect against inadvertent write attempts to the status register. The $\overline{\text{HOLD}}$ pin may be used to suspend any serial communication without resetting the serial sequence.

1. Absolute Maximum Ratings*

Operating Temperature55°C to +125°C	*NOTICE: Stresses beyond those listed under "Absolute Maximum Ratings" may cause perma-
Storage Temperature65°C to + 150°C	nent damage to the device. This is a stress rating only and functional operation of the
Voltage on Any Pin	device at these or any other conditions
with Respect to Ground1.0 V +7.0V	beyond those indicated in the operational
Maximum Operating Voltage6.25V	sections of this specification are not implied. Exposure to absolute maximum rating conditions for extended periods may affect.
DC Output Current5.0 mA	ditions for extended periods may affect device reliability.

Figure 1-1. Block Diagram

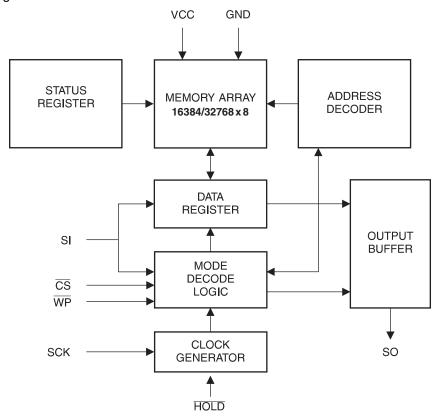


Table 1-1. Pin Capacitance $^{(1)}$ Applicable over recommended operating range from $T_A = 25^{\circ}C$, f = 1.0 MHz, $V_{CC} = +5.0$ V (unless otherwise noted)

Symbol	Test Conditions	Max	Units	Conditions
C _{OUT}	Output Capacitance (SO)	8	pF	VOUT = 0V
C _{IN}	Input Capacitance (\overline{CS} , SCK, SI, \overline{WP} , \overline{HOLD})	6	pF	VIN = 0V

Notes: 1. This parameter is characterized and is not 100% tested.





Table 1-2. DC Characteristics

Applicable over recommended operating range from $T_A = -40^{\circ}C$ to +85°C, $V_{CC} = +1.8V$ to +5.5V, $V_{CC} = +1.8V$ to +5.5V(unless otherwise noted)

Symbol	Parameter	Test Condition		Min	Тур	Max	Units
V _{CC1}	Supply Voltage		1.8		5.5	٧	
V _{CC2}	Supply Voltage			2.5		5.5	٧
V _{CC3}	Supply Voltage			4.5		5.5	٧
I _{CC1}	Supply Current	$V_{CC} = 5.0V \text{ at } 20 \text{ MHz},$	SO = Open, Read		9.0	10.0	mA
I _{CC2}	Supply Current	$V_{CC} = 5.0V \text{ at } 10 \text{ MHz},$	SO = Open, Read, Write		5.0	7.0	mA
I _{CC3}	Supply Current	V _{CC} = 5.0V at 1 MHz, S	O = Open, Read, Write		2.2	3.5	mA
I _{SB1}	Standby Current	$V_{CC} = 1.8V, \overline{CS} = V_{CC}$	$V_{CC} = 1.8V, \overline{CS} = V_{CC}$			3.0	μA
I _{SB2}	Standby Current	$V_{CC} = 2.5V, \overline{CS} = V_{CC}$	$V_{CC} = 2.5V, \overline{CS} = V_{CC}$			3.0	μA
I _{SB3}	Standby Current	$V_{CC} = 5.0V, \overline{CS} = V_{CC}$	$V_{CC} = 5.0V, \overline{CS} = V_{CC}$			5.0	μA
I _{IL}	Input Current	V _{IN} = 0V to V _{CC}	V _{IN} = 0V to V _{CC}			3.0	μA
I _{OL}	Output Leakage	$V_{IN} = 0V \text{ to } V_{CC}, T_{AC} = 0$	0°C to 70°C	-3.0		3.0	μA
V _{IL} ⁽¹⁾	Input Low-voltage			-1.0		V _{CC} x 0.3	٧
V _{IH} ⁽¹⁾	Input High-voltage			V _{CC} x 0.7		V _{CC} + 0.5	٧
V _{OL1}	Output Low-voltage	0.01/ ()/ (5.51/	I _{OL} = 3.0 mA			0.4	٧
V _{OH1}	Output High-voltage	$3.6V \le V_{CC} \le 5.5V$	$I_{OH} = -1.6 \text{ mA}$	V _{CC} - 0.8			٧
V _{OL2}	Output Low-voltage	4.07.47	I _{OL} = 0.15 mA			0.2	٧
V _{OH2}	Output High-voltage	$1.8V \le V_{CC} \le 3.6V$	I _{OH} = -100 μA	V _{CC} - 0.2			٧

Notes: 1. V_{IL} min and V_{IH} max are reference only and are not tested.

Table 1-3. AC Characteristics

Applicable over recommended operating range from $T_A = -40^{\circ}\text{C}$ to $+85^{\circ}\text{C}$, $V_{CC} = \text{As Specified}$, CL = 1 TTL Gate and 30 pF (unless otherwise noted)

Symbol	Parameter	Voltage	Min	Max	Units
f _{SCK}	SCK Clock Frequency	4.5–5.5 2.5–5.5 1.8–5.5	0 0 0	20 10 5	MHz
t _{RI}	Input Rise Time	4.5–5.5 2.5–5.5 1.8–5.5		2 2 2	μs
t _{FI}	Input Fall Time	4.5–5.5 2.5–5.5 1.8–5.5		2 2 2	μs
t _{WH}	SCK High Time	4.5–5.5 2.5–5.5 1.8–5.5	20 40 80		ns

Table 1-3. AC Characteristics (Continued)

Applicable over recommended operating range from $T_A = -40^{\circ}\text{C}$ to $+85^{\circ}\text{C}$, $V_{CC} = \text{As Specified}$, CL = 1 TTL Gate and 30 pF (unless otherwise noted)

Symbol	Parameter	Voltage	Min	Max	Units
t _{wL}	SCK Low Time	4.5–5.5 2.5–5.5 1.8–5.5	20 40 80		ns
t _{cs}	CS High Time	4.5–5.5 2.5–5.5 1.8–5.5	100 100 200		ns
t_{css}	CS Setup Time	4.5–5.5 2.5–5.5 1.8–5.5	100 100 200		ns
t _{csh}	CS Hold Time	4.5–5.5 2.5–5.5 1.8–5.5	100 100 200		ns
t _{su}	Data In Setup Time	4.5–5.5 2.5–5.5 1.8–5.5	5 10 20		ns
t _H	Data In Hold Time	4.5–5.5 2.5–5.5 1.8–5.5	5 10 20		ns
t _{HD}	HOLD Setup Time	4.5–5.5 2.5–5.5 1.8–5.5	5 10 20		ns
t _{CD}	HOLD Hold Time	4.5–5.5 2.5–5.5 1.8–5.5	5 10 20		ns
t _v	Output Valid	4.5–5.5 2.5–5.5 1.8–5.5	0 0 0	20 40 80	ns
t _{HO}	Output Hold Time	4.5–5.5 2.5–5.5 1.8–5.5	0 0 0		ns
t _{LZ}	HOLD to Output Low Z	4.5–5.5 2.5–5.5 1.8–5.5	0 0 0	25 50 100	ns
t _{HZ}	HOLD to Output High Z	4.5–5.5 2.5–5.5 1.8–5.5		25 50 100	ns
t _{DIS}	Output Disable Time	4.5–5.5 2.5–5.5 1.8–5.5		25 50 100	ns
t _{WC}	Write Cycle Time	4.5–5.5 2.5–5.5 1.8–5.5		5 5 5	ms
Endurance ⁽¹⁾	3.3V, 25°C, Page Mode		1M		Write Cycles

Notes: 1. This parameter is characterized and is not 100% tested. Contact Atmel for further information.





1.1 Serial Interface Description

MASTER: The device that generates the serial clock.

SLAVE: Because the serial clock pin (SCK) is always an input, the AT25128B/256B always operates as a slave.

TRANSMITTER/RECEIVER: The AT25128B/256B has separate pins designated for data transmission (SO) and reception (SI).

MSB: The Most Significant Bit (MSB) is the first bit transmitted and received.

SERIAL-OP CODE: After the device is selected with \overline{CS} going low, the first byte will be received. This byte contains the op-code that defines the operations to be performed.

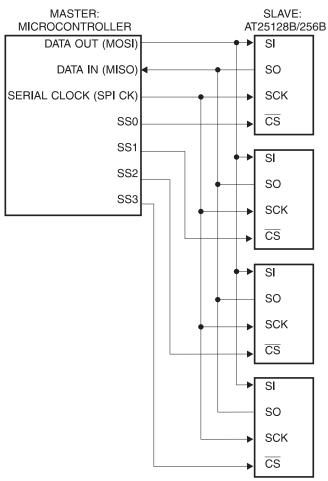
INVALID OP-CODE: If an invalid op-code is received, no data will be shifted into the AT25128B/256B, and the serial output pin (SO) will remain in a high impedance state until the falling edge of \overline{CS} is detected again. This will reinitialize the serial communication.

CHIP SELECT: The AT25128B/256B is selected when the \overline{CS} pin is low. When the device is not selected, data will not be accepted via the SI pin, and the serial output pin (SO) will remain in a high impedance state.

HOLD: The HOLD pin is used in conjunction with the CS pin to select the AT25128B/256B. When the device is selected and a serial sequence is underway, HOLD can be used to pause the serial communication with the master device without resetting the serial sequence. To pause, the HOLD pin must be brought low while the SCK pin is low. To resume serial communication, the HOLD pin is brought high while the SCK pin is low (SCK may still toggle during HOLD). Inputs to the SI pin will be ignored while the SO pin is in the high impedance state.

WRITE PROTECT: The write protect pin (\overline{WP}) will allow normal read/write operations when held high. When the \overline{WP} pin is brought low and WPEN bit is "1", all write operations to the status register are inhibited. \overline{WP} going low while \overline{CS} is still low will interrupt a write to the status register. If the internal write cycle has already been initiated, \overline{WP} going low will have no effect on any write operation to the status register. The \overline{WP} pin function is blocked when the WPEN bit in the status register is "0". This will allow the user to install the AT25128B/256B in a system with the \overline{WP} pin tied to ground and still be able to write to the status register. All \overline{WP} pin functions are enabled when the WPEN bit is set to "1".

Figure 1-2. SPI Serial Interface



2. Functional Description

The AT25128B/256B is designed to interface directly with the synchronous serial peripheral interface (SPI) of the 6800 type series of microcontrollers.

The AT25128B/256B utilizes an 8-bit instruction register. The list of instructions and their operation codes are contained in Table 2-1. All instructions, addresses, and data are transferred with the MSB first and start with a high-to-low $\overline{\text{CS}}$ transition.

Table 2-1. Instruction Set for the AT25128B/256B

Instruction Name	Instruction Format	Operation
WREN	0000 X110	Set Write Enable Latch
WRDI	0000 X100	Reset Write Enable Register
RDSR	0000 X101	Read Status Register





Table 2-1. Instruction Set for the AT25128B/256B

Instruction Name	Instruction Format	Operation	
WRSR	0000 X001	Write Status Register	
READ	0000 X011	Read Data from Memory Array	
WRITE	0000 X 010	Write Data to Memory Array	

WRITE ENABLE (WREN): The device will power-up in the write disable state when VCC is applied. All programming instructions must therefore be preceded by a Write Enable instruction.

WRITE DISABLE (WRDI): To protect the device against inadvertent writes, the Write Disable instruction disables all programming modes. The WRDI instruction is independent of the status of the $\overline{\text{WP}}$ pin.

READ STATUS REGISTER (RDSR): The Read Status Register instruction provides access to the status register. The Ready/Busy and Write Enable status of the device can be determined by the RDSR instruction. Similarly, the Block Write Protection bits indicate the extent of protection employed. These bits are set by using the WRSR instruction.

Table 2-2. Status Register Format

Bit 7	Bit 6	Bit 5	Bit 4	Bit 3	Bit 2	Bit 1	Bit 0
WPEN	Х	Х	Х	BP1	BP0	WEN	RDY

Table 2-3. Read Status Register Bit Definition

Bit	Definition	
Bit 0 (RDY)	Bit $0 = "0"$ (\overline{RDY}) indicates the device is ready. Bit $0 = "1"$ indicates the write cycle is in progress.	
Bit 1 (WEN)	Bit 1 = 0 indicates the device is not write enabled. Bit 1 = "1" indicates the device is write enabled.	
Bit 2 (BP0)	See Table 2-4 on page 9.	
Bit 3 (BP1)	See Table 2-4 on page 9.	
Bits 4 – 6 are 0s when device	e is not an internal write cycle.	
Bit 7 (WPEN) See Table 2-5 on page 9		
Bits 0 – 7 are "1"s during an	internal write cycle.	

WRITE STATUS REGISTER (WRSR): The WRSR instruction allows the user to select one of four levels of protection. The AT25128B/256B is divided into four array segments. Top quarter (1/4), top half (1/2), or all of the memory segments can be protected. Any of the data within any selected segment will therefore be read only. The block write protection levels and corresponding status register control bits are shown in Table 2-4.

The three bits, BP0, BP1, and WPEN are nonvolatile cells that have the same properties and functions as the regular memory cells (e.g. WREN, tWC, RDSR).

Table 2-4. Block Write Protect Bits

Level	vel Status Register Bits		Array Addresses Protected		
	BP1	BP0	AT25128B	AT25256B	
0	0	0	None	None	
1 (1/4)	0	1	3000 – 3FFF	6000 – 7FFF	
2 (1/2)	1	0	2000 – 3FFF	4000 – 7FFF	
3 (All)	1	1	0000 – 3FFF	0000 – 7FFF	

The WRSR instruction also allows the user to enable or disable the write protect (\overline{WP}) pin through the use of the write protect enable (WPEN) bit. Hardware write protection is enabled when the \overline{WP} pin is low and the WPEN bit is "1". Hardware write protection is disabled when either the \overline{WP} pin is high or the WPEN bit is "0". When the device is hardware write protected, writes to the Status Register, including the Block Protect bits and the WPEN bit, and the block-protected sections in the memory array are disabled. Writes are only allowed to sections of the memory which are not block-protected.

NOTE: When the WPEN bit is hardware write protected, it cannot be changed back to "0", as long as the \overline{WP} pin is held low.

Table 2-5. WPEN Operation

WPEN	WP	WEN	Protected Blocks	Unprotected Blocks	Status Register
0	Х	0	Protected	Protected	Protected
0	Х	1	Protected	Writable	Writable
1	Low	0	Protected	Protected	Protected
1	Low	1	Protected	Writable	Protected
Х	High	0	Protected	Protected	Protected
Х	High	1	Protected	Writable	Writable

READ SEQUENCE (READ): Reading the AT25128B/256B via the SO pin requires the following sequence. After the \overline{CS} line is pulled low to select a device, the Read op-code is transmitted via the SI line followed by the byte address to be read (Table 2-6). Upon completion, any data on the SI line will be ignored. The data (D7 - D0) at the specified address is then shifted out onto the SO line. If only one byte is to be read, the \overline{CS} line should be driven high after the data comes out. The read sequence can be continued since the byte address is automatically incremented and data will continue to be shifted out. When the highest address is reached, the address counter will roll over to the lowest address allowing the entire memory to be read in one continuous read cycle.

WRITE SEQUENCE (WRITE): In order to program the AT25128B/256B, two separate instructions must be executed. First, the device must be write enabled via the Write Enable (WREN) Instruction. Then a Write instruction may be executed. Also, the address of the memory location(s) to be programmed must be outside the protected address field location selected by the Block Write Protection Level. During an internal write cycle, all commands will be ignored except the RDSR instruction.

A Write Instruction requires the following sequence. After the \overline{CS} line is pulled low to select the device, the Write op-code is transmitted via the SI line followed by the byte address and the data





 $\overline{\text{CS}}$ pin is brought high. (The Low-to-High transition of the $\overline{\text{CS}}$ pin must occur during the SCK low time immediately after clocking in the D0 (LSB) data bit.

The Ready/Busy status of the device can be determined by initiating a Read Status Register (RDSR) Instruction. If Bit 0 = 1, the Write cycle is still in progress. If Bit 0 = 0, the Write cycle has ended. Only the Read Status Register instruction is enabled during the Write programming cycle.

The AT25128B/256B is capable of a 64-byte Page Write operation. After each byte of data is received, the six low order address bits are internally incremented by one; the high order bits of the address will remain constant. If more than 64 bytes of data are transmitted, the address counter will roll over and the previously written data will be overwritten. The AT25128B/256B is automatically returned to the write disable state at the completion of a Write cycle.

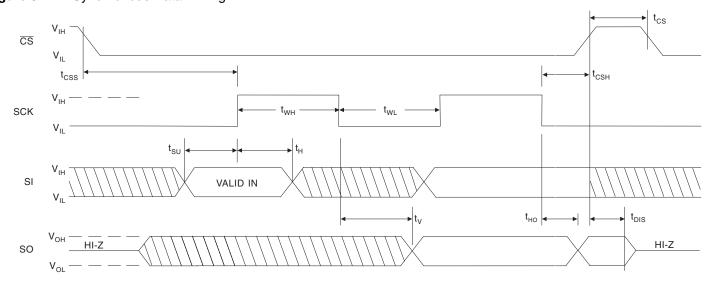
Note: If the device is not write enabled (WREN), the device will ignore the Write instruction and will return to the standby state, when \overline{CS} is brought high. A new \overline{CS} falling edge is required to re-initiate the serial communication.

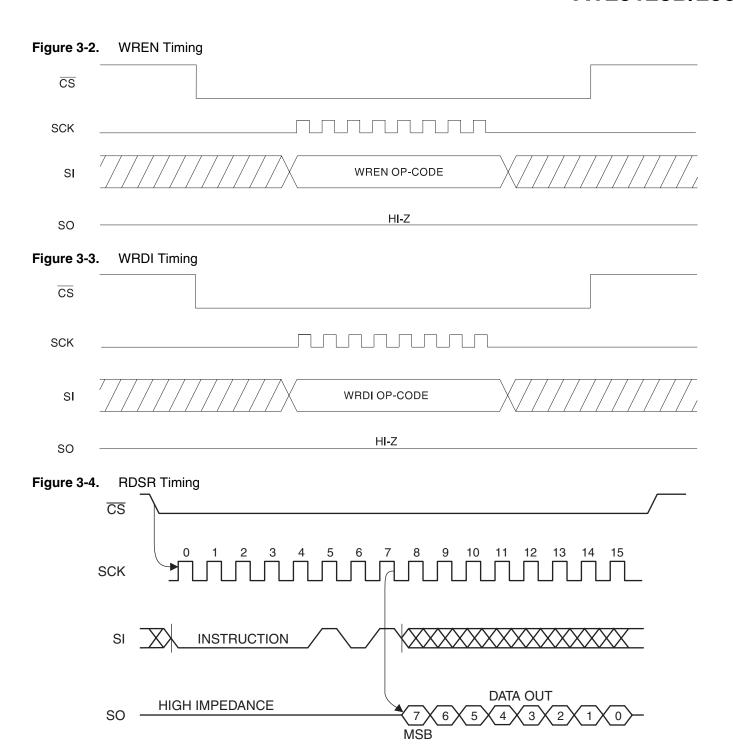
Table 2-6. Address Key

Address	AT25128B	AT25256B
A _N	$A_{13} - A_0$	$A_{14} - A_0$
Don't Care Bits	A ₁₅ – A ₁₄	A ₁₅

3. Timing Diagram (for SPI Mode 0 (0,0)

Figure 3-1. Synchronous Data Timing









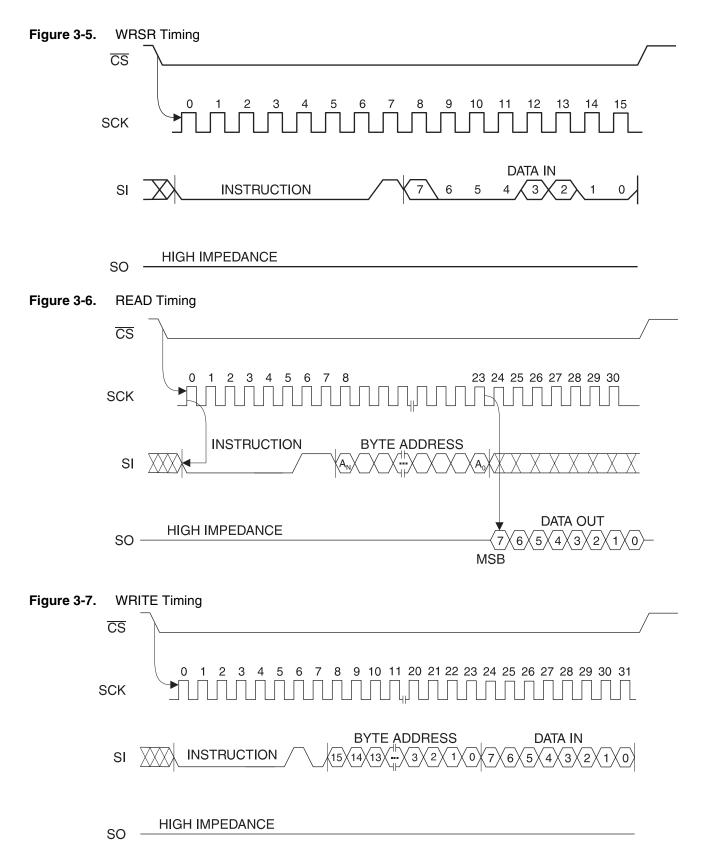


Figure 3-8. HOLD Timing

CS

SCK

HOLD

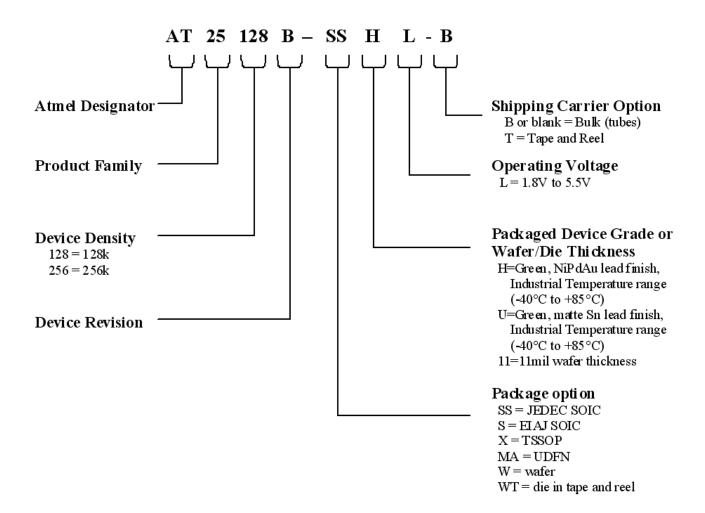
HOLD

SO





3.1 Catalog Numbering Scheme



4. Package Ordering Information

4.1 AT25128B Ordering Information

Table 4-1. AT25128B Ordering Information

Ordering Code	Package	Voltage Range	Operation Range
AT25128B-SSHL-B ⁽¹⁾	8S1	1.8V to 5.5V	
AT25128B-SSHL-T ⁽²⁾	8S1	1.8V to 5.5V	
AT25128B-XHL-B ⁽¹⁾	8A2	1.8V to 5.5V	Lead-free/Halogen-free/
AT25128B-XHL-T ⁽²⁾	8A2	1.8V to 5.5V	Industrial Temperature (-40°C to 85°C)
AT25128B-MAHL-T ⁽¹⁾	8MA2	1.8V to 5.5V	
AT25128B-CUL-T ⁽²⁾	8U2-1	1.8V to 5.5V	
AT25128B-W11L ⁽²⁾	Wafer	1.8V to 5.5V	Industrial Temperature
AT25128B-WT11L	Die in Tape	1.8V to 5.5V	(-40°C to 85°C)

Notes: 1. "U" designates Green package + RoHS compliant.

2. Available in waffle pack and wafer form; order as SL788 for wafer form. Bumped die available upon request. Please Contact Serial Interface Marketing.

	Package Type			
8S1	8-lead, 0.150" Wide, Plastic Gull Wing Small Outline Package (JEDEC SOIC)			
8U2-1	8-ball, die Ball Grid Array Package (VFBGA)			
8A2	8-lead, 4.40 mm Body, Plastic Thin Shrink Small Outline Package (TSSOP)			
8MA2	8-lead, 2.00 mm x 3.00 mm Body, 0.50 mm Pitch, Dual No Lead Package (UDFN)			





AT25256B Ordering Information 4.2

Table 4-2. AT25256B Ordering Information

Ordering Code	Package	Voltage Range	Operation Range
AT25256B-SSHL-B ⁽¹⁾	8S1	1.8V to 5.5V	
AT25256B-SSHL-T ⁽²⁾	8S1	1.8V to 5.5V	
AT25256B-SHL-B	8S2	1.8V to 5.5V	Lead-free/Halogen-free/
AT25256B-XHL-B ⁽¹⁾	8A2	1.8V to 5.5V	Industrial Temperature
AT25256B-XHL-T ⁽²⁾	8A2	1.8V to 5.5V	(-40°C to 85°C)
AT25256B-MAHL-T	8MA2	1.8V to 5.5V	
AT25256B-CUL-T ⁽¹⁾	8U2-1	1.8V to 5.5V	
AT25256B-W11L ⁽²⁾	Wafer	1.8V to 5.5V	Industrial Temperature
AT25256B-WT11L	Die in Tape	1.8V to 5.5V	(-40°C to 85°C)

- Notes: 1. "U" designates Green package + RoHS compliant.
 - 2. Available in waffle pack and wafer form; order as SL788 for wafer form. Bumped die available upon request. Please contact Serial Interface Marketing.

	Package Type			
8S1	8-lead, 0.150" Wide, Plastic Gull Wing Small Outline Package (JEDEC SOIC)			
8S2	8-lead, 0.209" Wide, Plastic Gull Wing Small Outline Package (EIAJ SOIC)			
8U2-1	8-ball, die Ball Grid Array Package (VFBGA)			
8A2	8-lead, 4.40 mm Body, Plastic Thin Shrink Small Outline Package (TSSOP)			
8MA2	8-lead, 2.00 mm x 3.00 mm Body, 0.50 mm Pitch, Dual No Lead Package (UDFN)			

5. AT25128B Part Markings

AT25128B-SSHL

```
Seal Year
TOP MARK
                  | Seal Week
                  |---|---|---|
   A T M L H Y W W
  |---|---|---|
   5 D B L
  |---|---|---|---|
   * Lot Number
  |---|---|---|
   Pin 1 Indicator (Dot)
@ = Country of Ass'y
Y = SEAL YEAR
                WW = SEAL WEEK
6: 2006
      0: 2010
                02 = Week 2
7: 2007
       1: 2011
                04 = Week 4
8: 2008
       2: 2012
                :: : :::: :
9: 2009
       3: 2013
                :: : :::: ::
                50 = Week 50
                52 = Week 52
```

AT25128B-XHL

TOP MARK

```
Pin 1 Indicator (Dot)
 1
 * |---|---|
   A T H Y W W
  |---|---|
    5 D B L
|---|---|---|
 ATMEL LOT NUMBER
|---|---|
@ = Country of Ass'y
Y = SEAL YEAR
                 WW = SEAL WEEK
8: 2008 2: 2012
                 02 = Week 2
9: 2009 3: 2013
                 04 = Week 4
0: 2010 4: 2014
1: 2011 5: 2015
                52 = Week 52
```





AT25128B-MAHL

TOP MARK

Pin 1 Indicator (Dot)

Y = YEAR OF ASSEMBLY

@ = Country of Ass'y

XX = ATMEL LOT NUMBER TO COORESPOND WITH

TRACE CODE LOG BOOK.

(e.g. XX = AA, AB, AC,...AX, AY, AZ)

Y = SEAL YEAR

6: 2006 0: 2010 7: 2007 1: 2011 8: 2008 2: 2012 9: 2009 3: 2013

AT25128B-CUL

```
TOP MARK
|---|---|
 5 D B U
|---|
 B Y M X X
|---|---|
 * <-- Pin 1 Indicator
   B = Country of Origin
   Y = One Digit Year Code
   M = One Digit Month Code
   XX = TRACE CODE (ATMEL LOT
       NUMBERS TO CORRESPOND
       WITH TRACE CODE LOG BOOK)
        (e.g. XX = AA, AB...YZ, ZZ)
Y = ONE DIGIT YEAR CODE
4: 2004 7: 2007
5: 2005
       8: 2008
6: 2006 9: 2009
M = SEAL MONTH (USE ALPHA DESIGNATOR A-L)
A = JANUARY
B = FEBRUARY
 J = OCTOBER
K = NOVEMBER
L = DECEMBER
```





6. AT25256B Part Markings

AT25256B-SSHL and AT25256B-SHL

```
Seal Year
TOP MARK
                 | Seal Week
                 |---|---|---|
   A T M L H Y W W
  |---|---|---|
   5 E B L
  |---|---|---|---|
   * Lot Number
  |---|---|---|
  Pin 1 Indicator (Dot)
@ = Country of Ass'y
Y = SEAL YEAR
              WW = SEAL WEEK
6: 2006 0: 2010 02 = Week 2
7: 2007
      1: 2011
               04 = Week 4
8: 2008
      2: 2012
                :: : :::: :
9: 2009
      3: 2013
               50 = Week 50
                52 = Week 52
```

AT25256B-XHL

TOP MARK

```
Pin 1 Indicator (Dot)
 * |---|---|
   A T H Y W W
  |---|---|
    5 E B L
|---|---|---|
 ATMEL LOT NUMBER
|---|---|---|
@ = Country of Ass'y
Y = SEAL YEAR
                WW = SEAL WEEK
8: 2008 2: 2012
                 02 = Week 2
9: 2009 3: 2013
                 04 = Week 4
0: 2010 4: 2014
                 52 = Week 52
1: 2011 5: 2015
```

AT25256B-MAHL

TOP MARK

Pin 1 Indicator (Dot)

Y = YEAR OF ASSEMBLY

@ = Country of Ass'y

XX = ATMEL LOT NUMBER TO COORESPOND WITH

TRACE CODE LOG BOOK.

(e.g. XX = AA, AB, AC,...AX, AY, AZ)

Y = SEAL YEAR



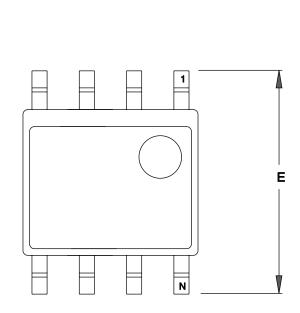


AT25256B-CUL

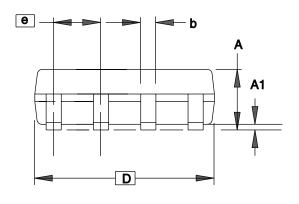
```
TOP MARK
|---|---|
 5 E B U
|---|---|
 B Y M X X
|---|---|
 * <-- Pin 1 Indicator
   B = Country of Origin
   Y = One Digit Year Code
   M = One Digit Month Code
   XX = TRACE CODE (ATMEL LOT
       NUMBERS TO CORRESPOND
       WITH TRACE CODE LOG BOOK)
        (e.g. XX = AA, AB...YZ, ZZ)
Y = ONE DIGIT YEAR CODE
4: 2004 7: 2007
5: 2005
       8: 2008
6: 2006 9: 2009
M = SEAL MONTH (USE ALPHA DESIGNATOR A-L)
A = JANUARY
B = FEBRUARY
 J = OCTOBER
K = NOVEMBER
L = DECEMBER
```

7. Packaging Information

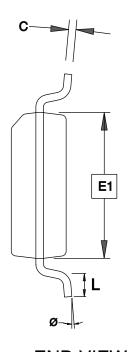
7.1 8S1 - JEDEC SOIC



TOP VIEW



SIDE VIEW



END VIEW

COMMON DIMENSIONS (Unit of Measure = mm)

SYMBOL	MIN	NOM	MAX	NOTE
Α	1.35	_	1.75	
A1	0.10	_	0.25	
b	0.31	_	0.51	
С	0.17	_	0.25	
D	4.80	-	5.05	
E1	3.81	_	3.99	
E	5.79	_	6.20	
е		1.27 BSC		
L	0.40	_	1.27	
q	0°	_	8°	

Note: These drawings are for general information only. Refer to JEDEC Drawing MS-012, Variation AA for proper dimensions, tolerances, datums, etc. 7/17/09



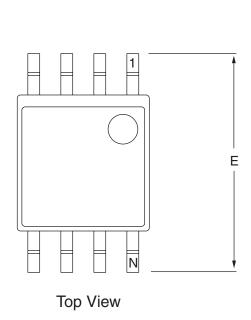
TITLE
8S1, 8-lead (0.150" Wide Body), Plastic Gull
Wing Small Outline (JEDEC SOIC)

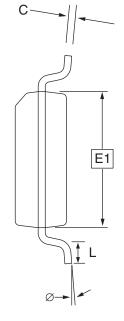
	• • • •	.,
GPC	DRAWING NO.	REV.
SWB	8S1	D



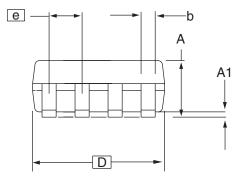


7.2 **8S2 - EIAJ**





End View



Side View

COMMON DIMENSIONS (Unit of Measure = mm)

SYMBOL	MIN	NOM	MAX	NOTE
Α	1.70		2.16	
A1	0.05		0.25	
b	0.35		0.48	5
С	0.15		0.35	5
D	5.13		5.35	
E1	5.18		5.40	2, 3
Е	7.70		8.26	
L	0.51		0.85	
Ø	0°		8°	
е		1.27 BSC		4

- Notes: 1. This drawing is for general information only; refer to EIAJ Drawing EDR-7320 for additional information.
 2. Mismatch of the upper and lower dies and resin burrs are not included.

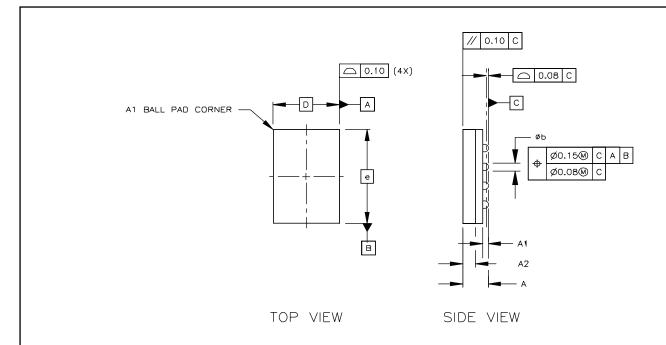
 - 3. It is recommended that upper and lower cavities be equal. If they are different, the larger dimension shall be regarded.

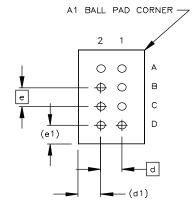
 - New York of the Standard that apper and level earlies be equal. If they are different, the target different shall be regarded.
 Determines the true geometric position.
 Values b and C apply to pb/Sn solder plated terminal. The standard thickness of the solder layer shall be 0.010 +0.010/-0.005 mm.

10/7/03

2325 Orchard Parkway San Jose, CA 95131	TITLE 8S2, 8-lead, 0.209" Body, Plastic Small Outline Package (EIAJ)	DRAWING NO. 8S2	REV.	
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7.3 **8U2-1 – VFBGA**





Notes:

BOTTOM VIEW 8 SOLDER BALLS

- 1. This drawing is for general information.
- 2. Dimension 'b' is measured at the maximum solder ball diameter.
- 3. Solder ball composition shall be 95.5Sn-4.0Ag-.5Cu.

COMMON DIMENSIONS

(Unit of Measure = mm)

SYMBOL	MIN	NOM	MAX	NOTE
Α	0.81	0.91	1.00	
A1	0.15	0.20	0.25	
A2	0.40	0.45	0.50	
b	0.25	0.30	0.35	
D	2			
E	3			
е	(
e1	(
d	0.75 BSC			
d1	().80 RE	ΞF	

2/25/08

С



Package Drawing Contact: packagedrawings@atmel.com

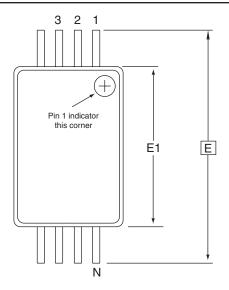
TITLE 8U2-1, 8 ball, 2.35 x 3.73 mm Body, 0.75 mm pitch VFBGA Package (VFBGA)

GPC DRAWING NO. REV. **GWW** 8U2-1

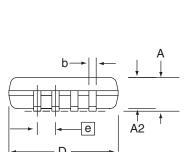




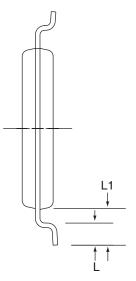
7.4 **8A2 - TSSOP**



Top View



Side View



End View

COMMON DIMENSIONS

(Unit of Measure = mm)

SYMBOL	MIN	NOM	MAX	NOTE
D	2.90	3.00	3.10	2, 5
Е		6.40 BSC		
E1	4.30	4.40	4.50	3, 5
Α	_	_	1.20	
A2	0.80	1.00	1.05	
b	0.19	-	0.30	4
е		0.65 BSC		
L	0.45	0.60	0.75	
L1	1.00 RE3			

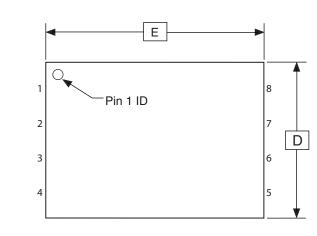
- Notes: 1. This drawing is for general information only. Refer to JEDEC Drawing MO-153, Variation AA, for proper dimensions, tolerances, datums, etc.
 - 2. Dimension D does not include mold Flash, protrusions or gate burrs. Mold Flash, protrusions and gate burrs shall not exceed 0.15 mm (0.006 in) per side.
 - 3. Dimension E1 does not include inter-lead Flash or protrusions. Inter-lead Flash and protrusions shall not exceed 0.25 mm (0.010 in) per side.
 - 4. Dimension b does not include Dambar protrusion. Allowable Dambar protrusion shall be 0.08 mm total in excess of the b dimension at maximum material condition. Dambar cannot be located on the lower radius of the foot. Minimum space between protrusion and adjacent lead is 0.07 mm.
 - 5. Dimension D and E1 to be determined at Datum Plane H.

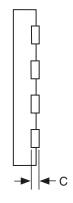
10/29/08 REV.

С

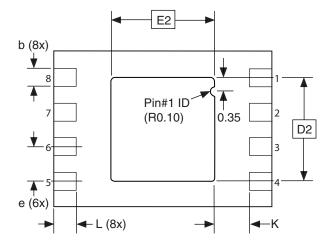


7.5 8MA2 - UDFN









COMMON DIMENSIONS

(Unit of Measure = mm)

SYMBOL	MIN	NOM	MAX	NOTE
D		2.00 BSC	;	
Е		3.00 BSC	;	
D2	1.40	1.50	1.60	
E2	1.20	1.30	1.40	
Α	0.50	0.55	0.60	
A1	0.0	0.02	0.05	
A2	_	_	0.55	
С		0.152 REF	F	
L	0.30	0.35	0.40	
е		0.50 BSC	;	
b	0.18	0.25	0.30	3
K	0.20	-	_	

Notes: 1. This drawing is for general information only. Refer to JEDEC Drawing MO-229, for proper dimensions, tolerances, datums, etc.

- 2. The terminal #1 ID is a laser-marked feature.
- 3. Dimension b applies to metallized terminal and is measured between 0.15 mm and 0.30 mm from the terminal tip. If the terminal has the optional radius on the other end of the terminal, the dimension should not be measured in that radius area.

4/15/08

			IIILE
	4 mei	Package Drawing Contact:	8MA2 , 8-pag
AIIIIEL	Package Drawing Contact: packagedrawings@atmel.com	Enhanced Pla	
	p	Load Backage	

IIILE	
8MA2 , 8-pad, 2 x 3 x 0.6 mm Body, Thermall	y
Enhanced Plastic Ultra Thin Dual Flat No	
Lead Package (UDFN)	

GPC	DRAWING NO.	REV.
YNZ	8MA2	А





8. Revision History

Doc. Rev.	Date	Comments
8698A	12/2009	Initial document release.



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